

# Soft X-ray Imager (SXI) onboard the NeXT satellite

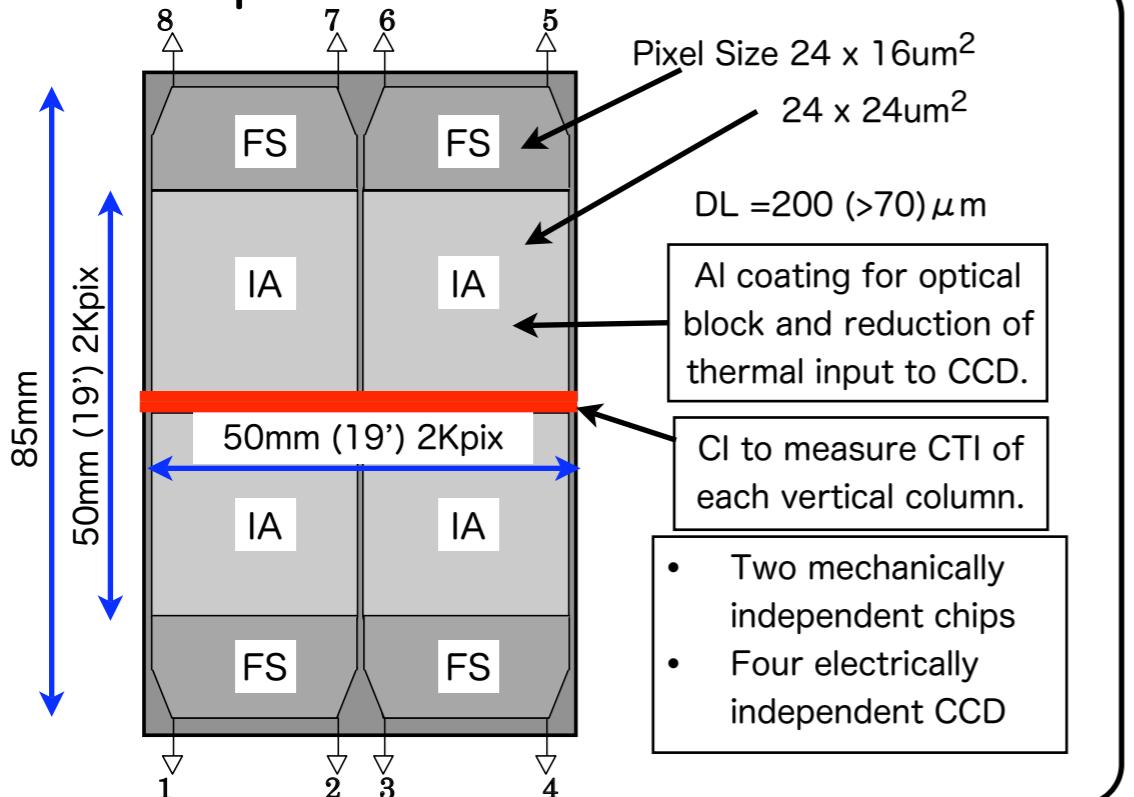
The NeXT/SXI Team

(Osaka Univ., Kyoto Univ., ISAS/JAXA, Rikkyo Univ., Ehime Univ., Kogakuin Univ.)

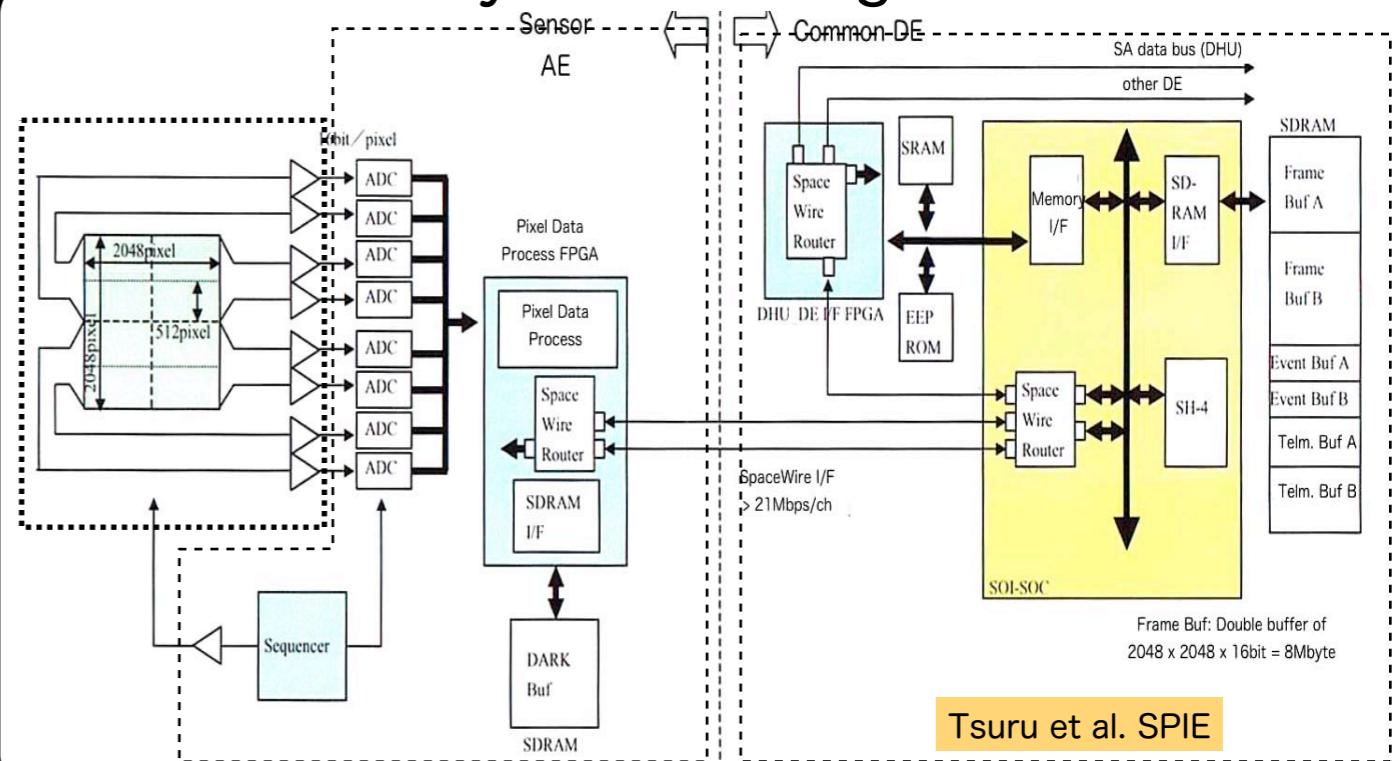


SXI is an X-ray CCD camera placed at the focal plane of Soft X-ray Telescopes for Imaging (SXT-I) onboard NeXT. The pixel size and the format of the imaging area of the CCD are  $24\mu\text{m} \times 24\mu\text{m}$  and  $2048 \times 2048$ , respectively. We have been developing two types of CCD as candidates for SXI, in parallel. The one is front illumination type CCD with moderate thickness of the depletion layer ( $70\sim100\mu\text{m}$ ) as a baseline plan. The other one is the goal plan, in which we develop back illumination type CCD with a thick depletion layer ( $200\sim300\mu\text{m}$ ). For the baseline plan, we successfully developed the proto-model 'CCD-NeXT1' with the pixel size of  $12\mu\text{m} \times 12\mu\text{m}$  and the CCD size of  $24\text{mm} \times 24\text{mm}$  in the imaging area. The goal plan is realized by introduction of a new type of CCD 'P-channel CCD', which collects holes in stead of electrons in the common 'N-channel CCD'. By processing a test model of P-channel CCD we have confirmed high quantum efficiency above 10 keV with an equivalent depletion layer of  $300\mu\text{m}$ . A back illumination type of P-channel CCD with a depletion layer of  $200\mu\text{m}$  with aluminum coating for optical blocking has been also successfully developed. We have been also developing a thermoelectric cooler (TEC) with the function of the mechanically support of the CCD wafer without standoff insulators, for the purpose of the reduction of thermal input to the CCD through the standoff insulators. We have been considering the sensor housing and the onboard electronics for the CCD clocking, readout and digital processing of the frame date. The detail of the development is found in Tsuru et al. 2006 (SPIE).

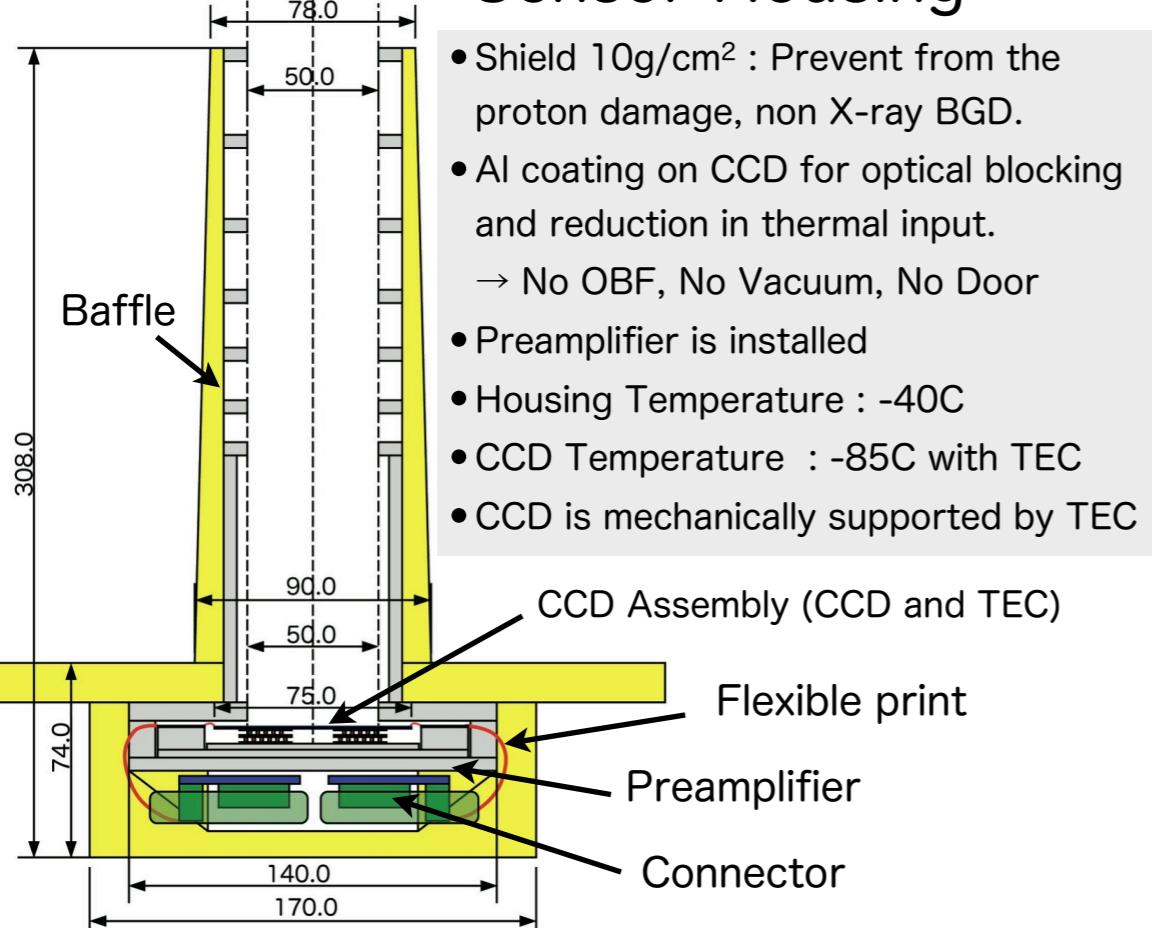
## Specification of the CCD



## System Configuration



## Sensor Housing

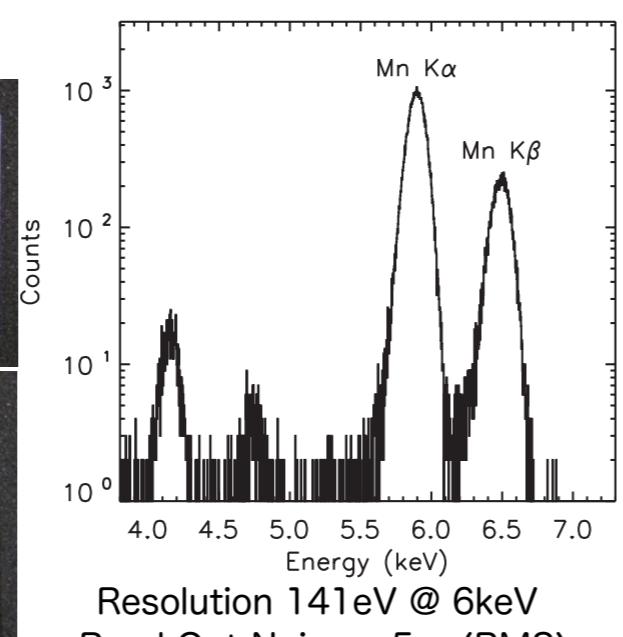
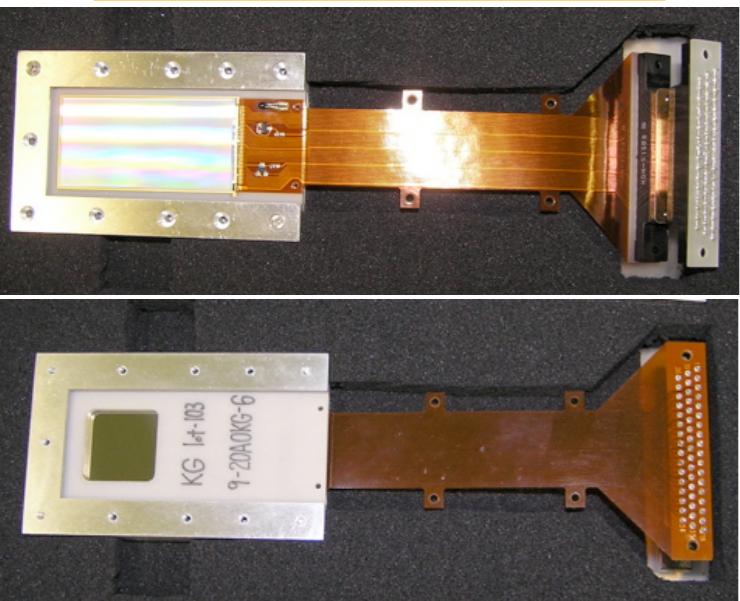


## Designing DE/AE

- Readout Cycle 4 sec (determined by anti-pile-up condition)
  - High speed CCD clocking impacts the readout noise.
    - Equip 8 read out nodes in order to keep 131 kHz.
  - CPU capacity of XIS-DE
    - Almost all the CPU time is used for the dark level subtraction of each pixel, which is proportional to the total pixel read out rate of the whole CCD.
    - XSI (1Mpix/sec) =  $2 \times$  XIS (0.5Mpix/sec)
  - Common DE (Space Cube for NeXT)
    - $100\text{-}200\text{MIPS} = (2\text{-}4) \times$  XIS-DE
    - Bench mark: Not impossible, but rather small margin.
    - Option: the hardwire event extraction with FPGA
  - SpaceWire I/F ( $>21\text{Mbps/ch}$ )
- Ozaki et al. (2001), Anabuki et al. (2002)

## N-ch CCD : CCD-NeXT1

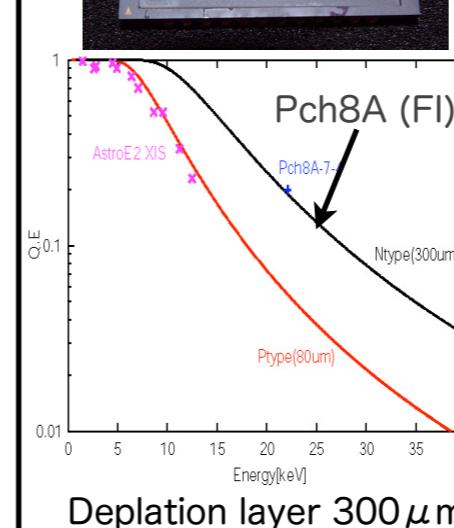
Ozawa et al. SPIE. This Conf.



- FI, depletion:  $75\text{-}85\mu\text{m}$  + field free:  $65\text{-}75\mu\text{m}$
- $24 \times 24\text{mm}^2 \times 2$  (IA + FS), pixel size  $12 \times 12\mu\text{m}^2$
- Back Supportless (according to the original WXI)

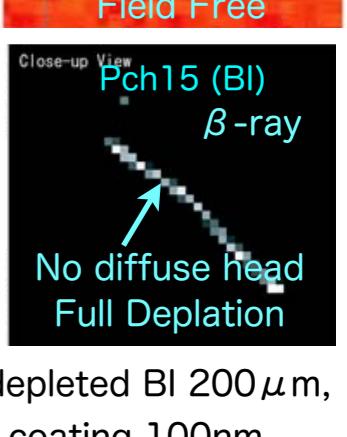
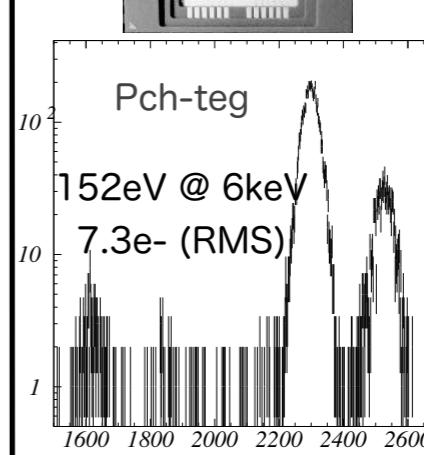
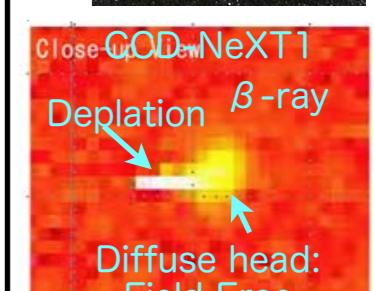
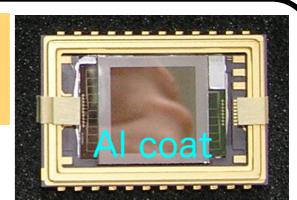
## P-ch CCD Test Device

Takagi et al. NIM (2005)



Takagi et al. SPIE, Thic Conf

Matsuura et al. SPIE, This Conf.



Fully depleted BI  $200\mu\text{m}$ , Al coating  $100\text{nm}$